

PATENT APPLICATION

[Document Name]	Patent Application
[Application Type]	Patent
[Receiver]	Commissioner
[Reference No.]	0005
[Filing Date]	2003.06.05.
[IPC]	G11C
[Title]	Semiconductor device and test method of testing the same
[Applicant]	
Name:	Samsung Electronics Co., Ltd.
Applicant code:	1-1998-104271-3
[Attorney]	
Name:	Young-pil Lee
Attorney's code:	9-1998-000334-6
Reg. No. of General	
Power of Attorney:	2003-003435-0
Name:	Sang-bin Jeong
Attorney's code:	9-1998-000541-1
Reg. No. of General	
Power of Attorney:	2003-003437-4
[Inventor]	
Name:	Seong-ho Jeung
I.D. No.	690610-1163125
Zip Code:	422-470
Address:	603-1202, Poonglim Apt, 967-2, Youngtong-dong, Paldal-gu, Suwon-city, Kyungki-do, Republic of Korea
Nationality:	Republic of Korea
[Inventor]	
Name:	Jong-hoon. Jung
I.D. No.	730625-1009718
Zip Code:	449-846
Address:	303, Noblehouse, 1148-10, Poongdeokcheon-ri, Suji-eup, Yongin-city, Kyungki-do, Republic of Korea
Nationality:	Republic of Korea

[Request for Examination] Requested

[Application Order] We respectively submit an application according to Art. 42 of the Patent Law and request an examination according to Art. 60 of the Patent Law, as above.

Attorney

Young-pil Lee (seal)

Attorney

Sang-bin Jeong (seal)

[Fee]

Basic page:	20 Sheet(s)	29,000 won
Additional page:	14 1 Sheet(s)	14,000 won
Priority claiming fee:	0 Case(s)	0 won
Examination fee:	250 Claim(s)	909,000 won
Total:		952,000 won

[Enclosures]

1. Abstract and Specification (and Drawings)

1 copy each